



**General Description**

- Proprietary  $\alpha$ MOS5™ technology
- Low  $R_{DS(ON)}$
- Optimized switching parameters for better EMI performance
- Enhanced body diode for robustness and fast reverse recovery

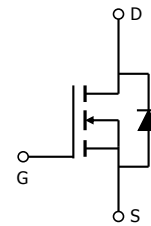
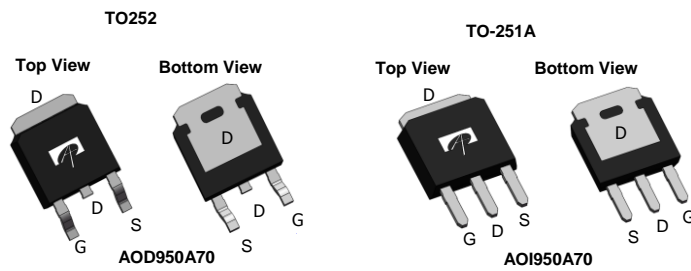
**Applications**

- Flyback for SMPS
- Charger, Adapter, lighting

**Product Summary**

$V_{DS} @ T_{j,max}$	800V
$I_{DM}$	20A
$R_{DS(ON),max}$	< 0.95 $\Omega$
$Q_{g,typ}$	10nC
$E_{oss} @ 400V$	1.2 $\mu$ J

100% UIS Tested  
100%  $R_g$  Tested



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOD950A70	TO-252	Tape & Reel	2500
AOI950A70	TO-251A	Tube	3500

**Absolute Maximum Ratings  $T_A=25^\circ\text{C}$  unless otherwise noted**

Parameter	Symbol	AOD950A70	AOI950A70	Units
Drain-Source Voltage	$V_{DS}$	700		V
Gate-Source Voltage	$V_{GS}$	$\pm 20$		V
Gate-Source Voltage (dynamic) AC( $f > 1\text{Hz}$ )	$V_{GS}$	$\pm 30$		V
Continuous Drain Current	$I_D$	$T_C=25^\circ\text{C}$	5	A
		$T_C=100^\circ\text{C}$	3.2	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	20		
Avalanche Current <sup>C</sup> $L=1\text{mH}$	$I_{AR}$	0.8		A
Repetitive avalanche energy <sup>C</sup>	$E_{AR}$	0.3		mJ
Single pulsed avalanche energy <sup>H</sup>	$E_{AS}$	7.5		mJ
MOSFET dv/dt ruggedness	dv/dt	100		V/ns
Peak diode recovery dv/dt		20		
Power Dissipation <sup>B</sup>	$P_D$	$T_C=25^\circ\text{C}$	56.5	W
		Derate above $25^\circ\text{C}$	0.45	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150		$^\circ\text{C}$
Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	$T_L$	300		$^\circ\text{C}$

**Thermal Characteristics**

Parameter	Symbol	AOD950A70	AOI950A70	Units
Maximum Junction-to-Ambient <sup>A,D</sup>	$R_{\theta JA}$	45	55	$^\circ\text{C}/\text{W}$
Maximum Case-to-sink <sup>A</sup>	$R_{\theta CS}$	-	0.5	$^\circ\text{C}/\text{W}$
Maximum Junction-to-Case <sup>D,F</sup>	$R_{\theta JC}$	2.2		$^\circ\text{C}/\text{W}$

**Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C	700	-	-	V
		I <sub>D</sub> =250μA, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C	-	800	-	
BV <sub>DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V	-	0.6	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =700V, V <sub>GS</sub> =0V	-	-	1	μA
		V <sub>DS</sub> =560V, T <sub>J</sub> =125°C	-	-	10	
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V	-	-	±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =5V, I <sub>D</sub> =250μA	2.9	3.5	4.1	V
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =1A	-	0.86	0.95	Ω
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =10V, I <sub>D</sub> =1A	-	2.2	-	S
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V	-	0.8	1.2	V
I <sub>S</sub>	Maximum Body-Diode Continuous Current		-	-	5	A
I <sub>SM</sub>	Maximum Body-Diode Pulsed Current <sup>C</sup>		-	-	20	A
<b>DYNAMIC PARAMETERS</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =100V, f=1MHz	-	461	-	pF
C <sub>oss</sub>	Output Capacitance		-	15	-	pF
C <sub>o(er)</sub>	Effective output capacitance, energy related <sup>H</sup>	V <sub>GS</sub> =0V, V <sub>DS</sub> =0 to 480V, f=1MHz	-	13.3	-	pF
C <sub>o(tr)</sub>	Effective output capacitance, time related <sup>I</sup>		-	59	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =100V, f=1MHz	-	1.4	-	pF
R <sub>g</sub>	Gate resistance	f=1MHz	-	5.9	-	Ω
<b>SWITCHING PARAMETERS</b>						
Q <sub>g</sub>	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =480V, I <sub>D</sub> =2.5A	-	10	-	nC
Q <sub>gs</sub>	Gate Source Charge		-	2.6	-	nC
Q <sub>gd</sub>	Gate Drain Charge		-	2.8	-	nC
t <sub>D(on)</sub>	Turn-On DelayTime	V <sub>GS</sub> =10V, V <sub>DS</sub> =400V, I <sub>D</sub> =2.5A, R <sub>G</sub> =5Ω	-	16	-	ns
t <sub>r</sub>	Turn-On Rise Time		-	7	-	ns
t <sub>D(off)</sub>	Turn-Off DelayTime		-	33	-	ns
t <sub>f</sub>	Turn-Off Fall Time		-	12	-	ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =2.5A, di/dt=100A/μs, V <sub>DS</sub> =400V	-	200	-	ns
I <sub>rm</sub>	Peak Reverse Recovery Current		-	13	-	A
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge		-	2	-	μC

A. The value of R<sub>θJA</sub> is measured with the device in a still air environment with T<sub>A</sub>=25° C.

B. The power dissipation P<sub>D</sub> is based on T<sub>J(MAX)</sub>=150° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature T<sub>J(MAX)</sub>=150° C. Ratings are based on low frequency and duty cycles to keep initial T<sub>J</sub>=25° C.

D. The R<sub>θJA</sub> is the sum of the thermal impedance from junction to case R<sub>θJC</sub> and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T<sub>J(MAX)</sub>=150° C.

G. These tests are performed with the device mounted on 1 in2 FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25° C.

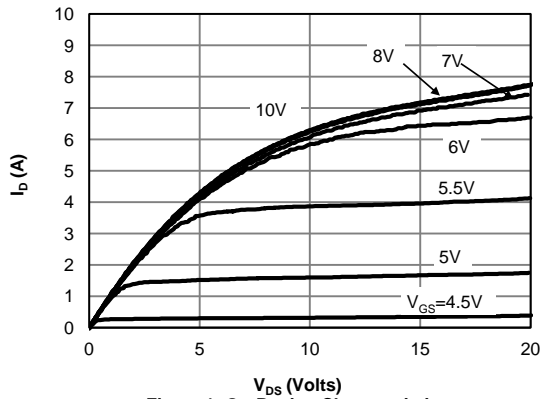
H. L=60mH, I<sub>AS</sub>=0.5A, R<sub>G</sub>=25Ω, Starting T<sub>J</sub>=25° C.

I. C<sub>o(er)</sub> is a fixed capacitance that gives the same stored energy as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>(BR)DSS</sub>.

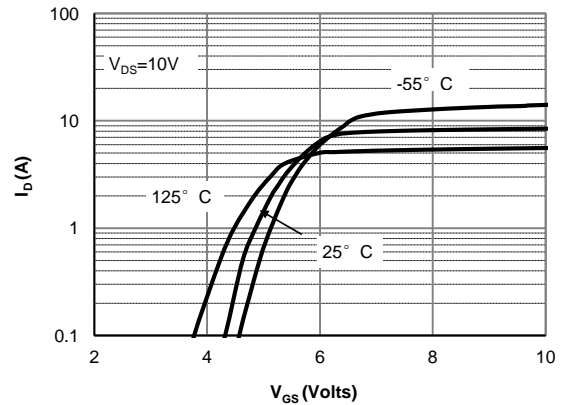
J. C<sub>o(tr)</sub> is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>(BR)DSS</sub>.

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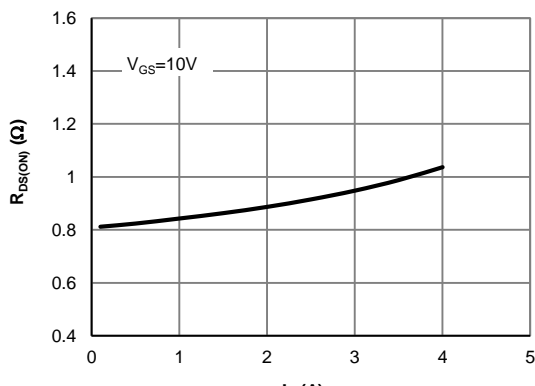
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**



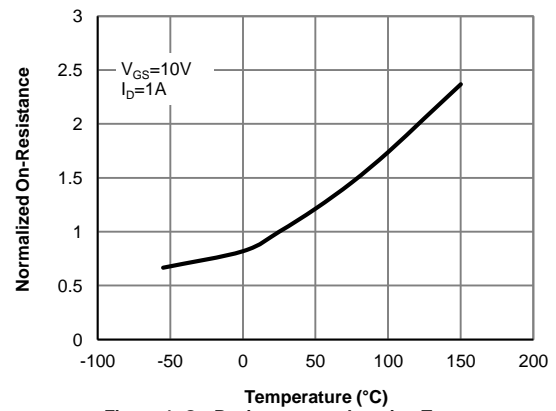
**Figure 1: On-Region Characteristics**



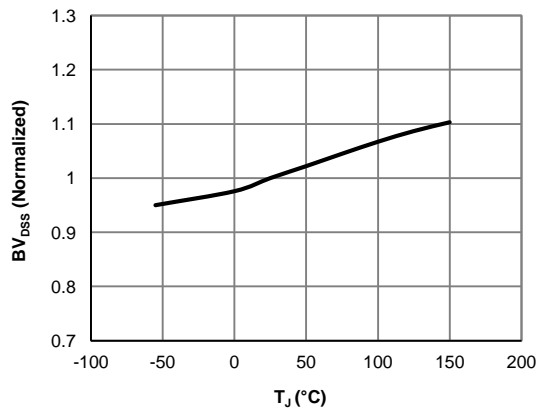
**Figure 2: Transfer Characteristics**



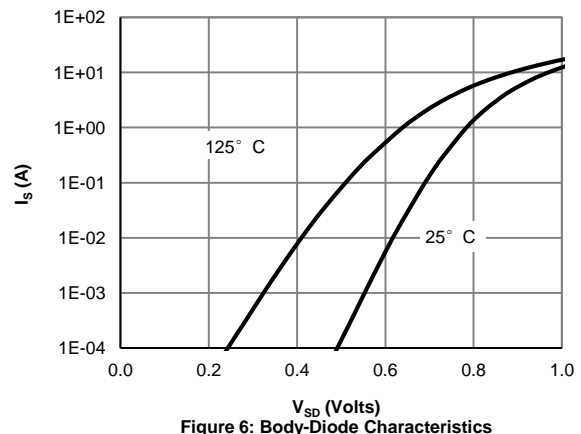
**Figure 3: On-Resistance vs. Drain Current and Gate Voltage**



**Figure 4: On-Resistance vs. Junction Temperature**

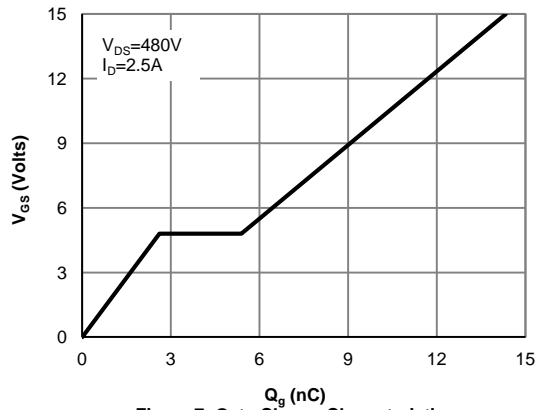


**Figure 5: Break Down vs. Junction Temperature**

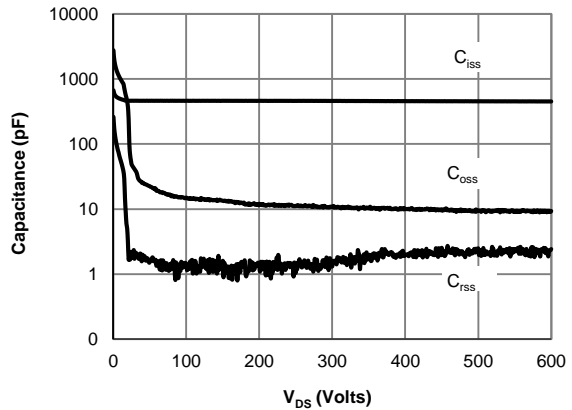


**Figure 6: Body-Diode Characteristics**

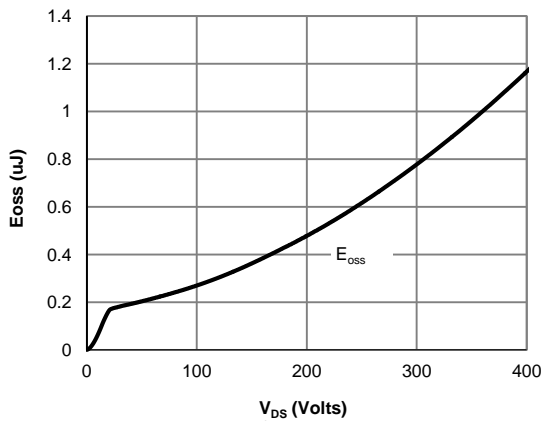
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**



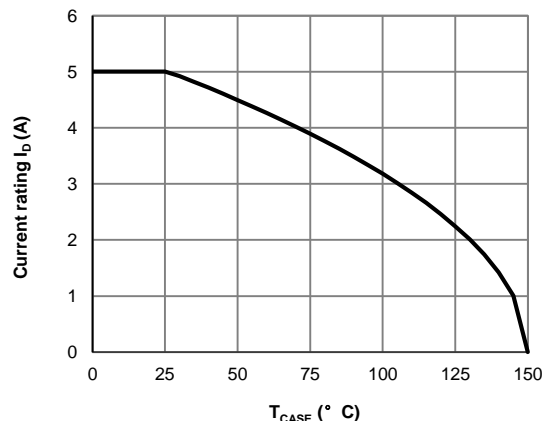
**Figure 7: Gate-Charge Characteristics**



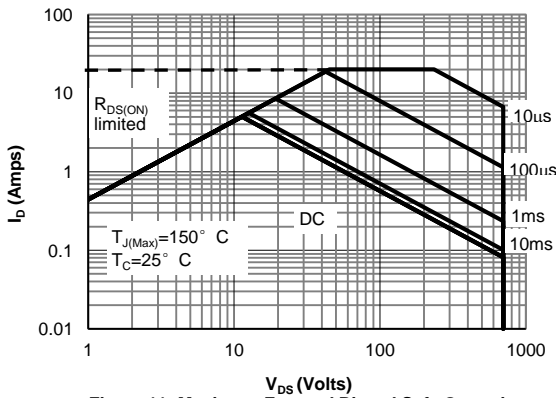
**Figure 8: Capacitance Characteristics**



**Figure 9: Coss stored Energy**



**Figure 10: Current De-rating (Note F)**



**Figure 11: Maximum Forward Biased Safe Operating Area for AOD(I)950A70 (Note F)**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

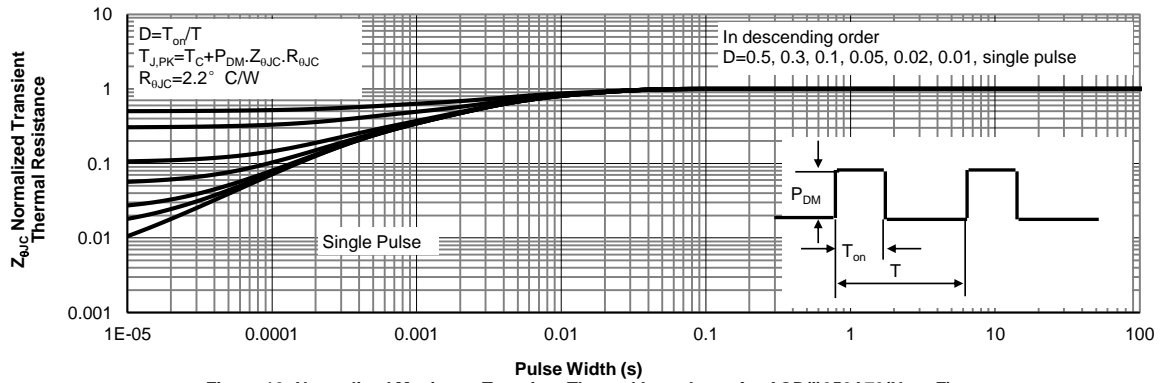
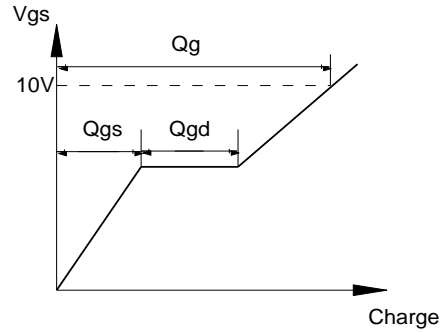
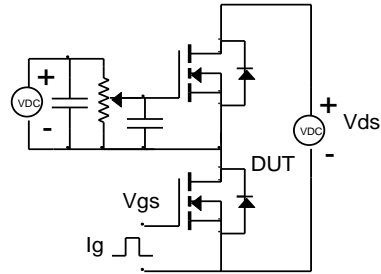
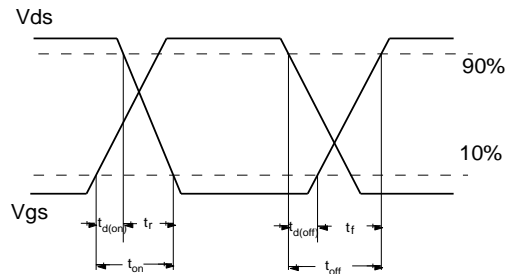
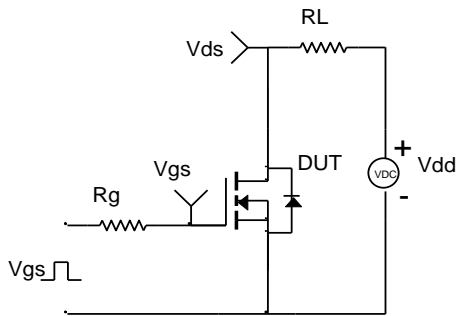


Figure 12: Normalized Maximum Transient Thermal Impedance for AOD(I)950A70(Note F)

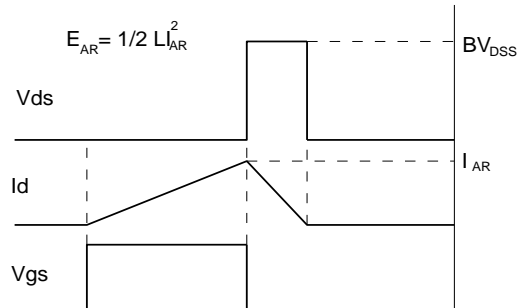
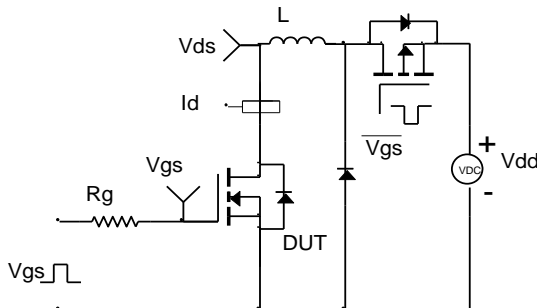
**Gate Charge Test Circuit & Waveform**



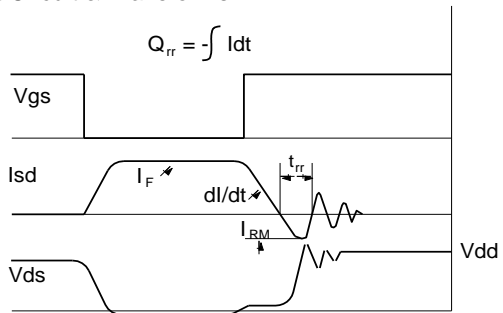
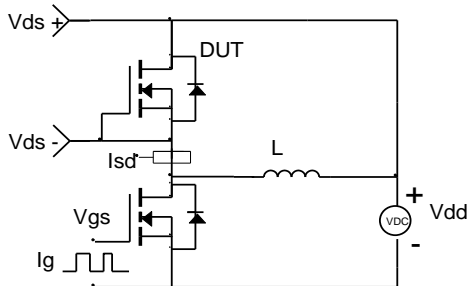
**Resistive Switching Test Circuit & Waveforms**



**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**



**Diode Recovery Test Circuit & Waveforms**



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